

UNISONIC TECHNOLOGIES CO., LTD

10N65Z **Power MOSFET**

10A, 650V N-CHANNEL POWER MOSFET

DESCRIPTION

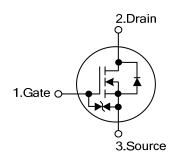
The UTC 10N65Z is a high voltage and high current power MOSFET, designed to have better characteristics, such as fast switching time, low gate charge, low on-state resistance and a high rugged avalanche characteristics. This power MOSFET is usually used at high speed switching applications in power supplies, PWM motor controls, high efficient DC to DC converters and bridge circuits.

TO-220F1

FEATURES

- * $R_{DS(ON)} = 0.95\Omega$ @ $V_{GS} = 10V$, $I_D = 4.75A$
- * Low gate charge (typical 44 nC)
- * Low Crss (typical 18 pF)
- * Fast switching
- * 100% avalanche tested
- * Improved dv/dt capability

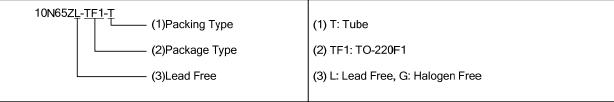
SYMBOL



ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
10N65ZL-TF1-T	10N65ZG-TF1-T	TO-220F1	G	D	S	Tube	

Note: Pin Assignment: G: Gate D: Drain S: Source



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■ **ABSOLUTE MAXIMUM RATINGS** (T_C = 25°C unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	650	V
Gate-Source Voltage		V_{GSS}	± 20	V
Avalanche Current (Note 2)		I_{AR}	10	Α
Drain Current	Continuous	I _D	10	Α
	Pulsed (Note 2)	I_{DM}	38	Α
Avalanche Energy	Single Pulsed (Note 3)	E _{AS}	110	mJ
	Repetitive (Note 2)	E_{AR}	15.6	mJ
Peak Diode Recovery dv/dt (Note 4)		dv/dt	4.5	V/ns
Power Dissipation		P_D	50	W
Junction Temperature		T_J	+150	°C
Operating Temperature		T_{OPR}	-55 ~ +150	°C
Storage Temperature		T_{STG}	-55 ~ +150	°C

Notes: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged.

Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Repetitive Rating: Pulse width limited by maximum junction temperature
- 3. L = 14.2mH, I_{AS} = 3.93A, V_{DD} = 50V, R_{G} = 25 Ω Starting T_{J} = 25°C
- 4. $I_{SD} \le 9.5A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATING	UNIT
Junction to Ambient	θ_{JA}	62.5	°C/W
Junction to Case	θ_{JC}	2.5	°C/W

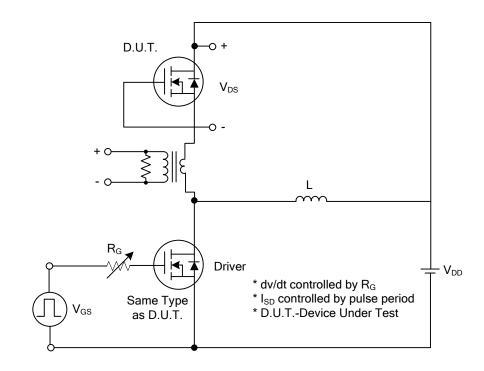
■ **ELECTRICAL CHARACTERISTICS**(T_C=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS		TYP	MAX	UNIT
OFF CHARACTERISTICS						
Drain-Source Breakdown Voltage	BV _{DSS}	V_{GS} =0V, I_{D} = 250 μ A	650			V
Drain-Source Leakage Current	I _{DSS}	V _{DS} =650V, V _{GS} =0V			1	μΑ
Gate-Source Leakage Current		Forward V _{GS} =20V, V _{DS} =0V			5	μΑ
Gate-Source Leakage Current	I _{GSS}	Reverse V _{GS} =-20V, V _{DS} =0V			-5	μΑ
Breakdown Voltage Temperature	Λ Ρ \/ /ΛΤ.	I _D =250 μA, Referenced to 25°C		0.7		V/°C
Coefficient	ZBVDSS/Z1J	ID-230 μA, Referenced to 25 C		0.7		V/ C
ON CHARACTERISTICS						
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	2.0		4.0	V
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =4.75A		0.87	0.95	Ω
DYNAMIC CHARACTERISTICS						
Input Capacitance	C _{ISS}			1300	2040	pF
Output Capacitance	Coss	V _{DS} =25V, V _{GS} =0V, f=1.0 MHz		135	215	pF
Reverse Transfer Capacitance	C _{RSS}			25	35	pF
SWITCHING CHARACTERISTICS						
Turn-On Delay Time	t _{D(ON)}			70	55	ns
Turn-On Rise Time	t_R	V_{DD} =325V, I_{D} =10A, R_{G} =25 Ω		145	150	ns
Turn-Off Delay Time	t _{D(OFF)}	(Note1, 2)		280	300	ns
Turn-Off Fall Time	t _F			135	165	ns
Total Gate Charge	Q_G	V 500V L 40A V 40V		124	140	nC
Gate-Source Charge	Q_{GS}	V _{DS} =520V, I _D =10A, V _{GS} =10V		26		nC
Gate-Drain Charge	Q_{GD}	(Note1, 2)		42		nC
DRAIN-SOURCE DIODE CHARACTERISTI	CS AND MA	XIMUM RATINGS	_	_	_	
Drain-Source Diode Forward Voltage	V_{SD}	V _{GS} =0V, I _S =10A			1.4	V
Maximum Continuous Drain-Source Diode					10	۸
Forward Current	I _S				10	Α
Maximum Pulsed Drain-Source Diode	la				38	Α
Forward Current	urrent I _{SM}				30	^
Reverse Recovery Time	t _{rr}	V _{GS} =0V, I _S =10A,		420		ns
Reverse Recovery Charge	Q_{RR}	dl _F /dt=100A/μs (Note1)		4.2		μC

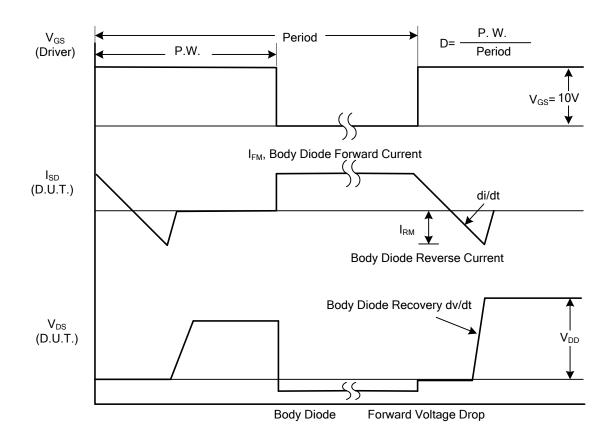
Notes: 1. Pulse Test : Pulse width ≤300µs, Duty cycle ≤2%

^{2.} Essentially independent of operating temperature

■ TEST CIRCUITS AND WAVEFORMS

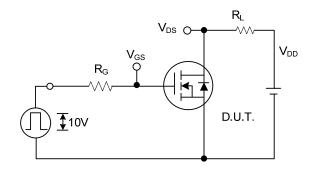


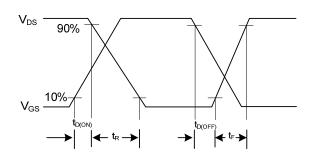
Peak Diode Recovery dv/dt Test Circuit



Peak Diode Recovery dv/dt Waveforms

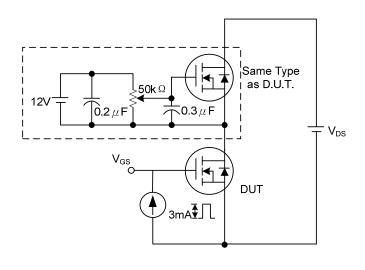
■ TEST CIRCUITS AND WAVEFORMS (Cont.)

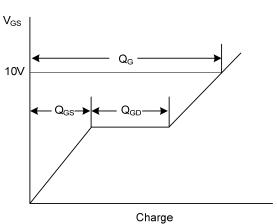




Switching Test Circuit

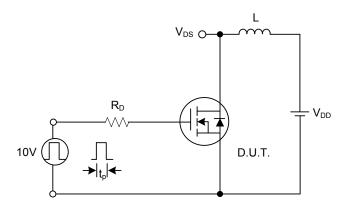
Switching Waveforms

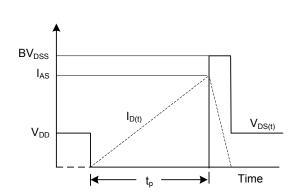




Gate Charge Test Circuit

Gate Charge Waveform





Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

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